

**Search Notes**

Application/Control No.

10/615,416

Examiner

Pablo Whaley

Applicant(s)/Patent under  
Reexamination

WISHART ET AL.

Art Unit

1631

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Google Scholar: NMR, FID, contaminant, filtering	9/21/2007	PW
Inventor Search: Palm	9/21/2007	PW